

N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY					
V_{DS}	100	V			
$R_{DS(on)} V_{GS} = 10 V$	32	mΩ			
I _D	9	Α			
Configuration	Single				

SO-8 D D D

Top View

D

100 % Avalanche Tested Compliant to RoHS Directive 2002/95/EC

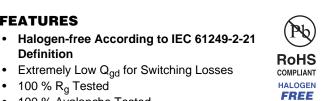
Definition

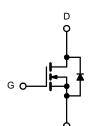
FEATURES

APPLICATIONS · Primary Side Switch

100 % R_g Tested

• Extremely Low Q_{gd} for Switching Losses





N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		9		
Continuous Drain Current (T = 150 °C)	T _C = 70 °C	1 ,	6		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	l _D	6 ^{b, c}		
	T _A = 70 °C		5 ^{b, c}		
Pulsed Drain Current		I _{DM}	40	Α	
Continuous Source-Drain Diode Current	T _C = 25 °C		7		
	T _A = 25 °C	I _S	3.8 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30		
ngle Pulse Avalanche Energy		E _{AS}	112	mJ	
	T _C = 25 °C		14		
Maximum Power Dissipation	T _C = 70 °C		5	W	
	T _A = 25 °C	P _D	4 ^{b, c}	VV	
	T _A = 70 °C		2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, †}	t ≤ 10 s	R_{thJA}	33	40	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	21	C/ V V	

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 80 °C/W.



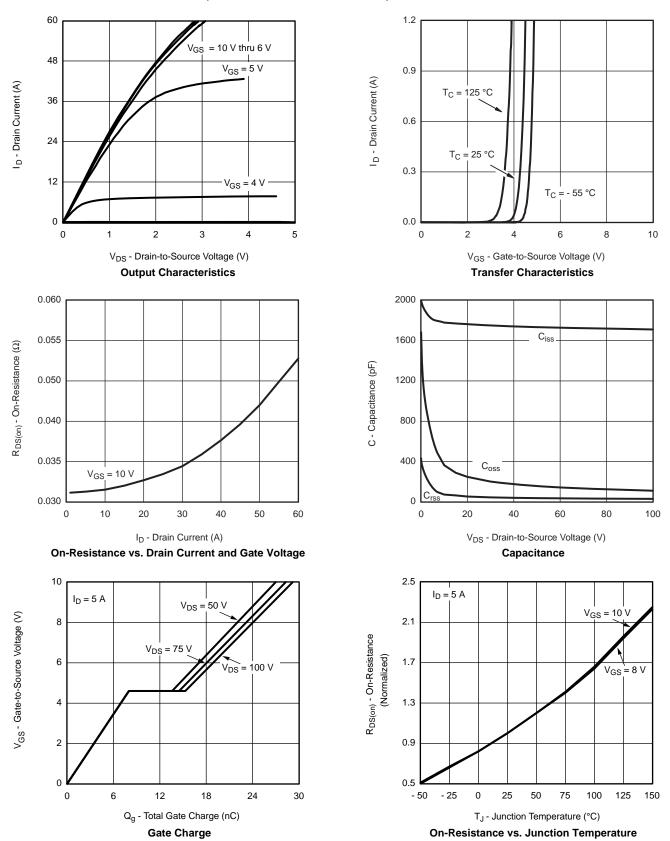
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•		1		•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			172		>//06	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 10		mV/°0	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0 0 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1		V _{DS} = 100 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≥ 10 V, V _{GS} = 10 V	30			Α	
Dunin Course On Ctata Desistance		$V_{GS} = 10 \text{ V, } I_{D} = 5 \text{ A}$		0.032	0.032		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$		0.033		mΩ	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5 A		20		S	
Dynamic ^b					•		
Input Capacitance	C _{iss}			1900			
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		150		pF	
Reverse Transfer Capacitance	C _{rss}			50			
Total Gate Charge	Q _g	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		28.5	43		
		$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		23	35	nC	
Gate-Source Charge	Q_{gs}			8			
Gate-Drain Charge	Q _{gd}			6.5			
Gate Resistance	R_{g}	f = 1 MHz		0.80	1.3	Ω	
Turn-on Delay Time	t _{d(on)}			14	21		
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18]	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33		
Fall Time	t _f			6	10	no	
Turn-On Delay Time	t _{d(on)}			16	24	ns	
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5$ A, $V_{GEN} = 8$ V, $R_g = 1$ Ω		20	30		
Fall Time	t _f			7	12		
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			7.7	۸	
Pulse Diode Forward Current ^a	I _{SM}	;M			50	A	
Body Diode Voltage	V_{SD}	I _S = 2.6 A		0.77	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 5 A dl/dt = 100 A/up T = 25 °C		110	165	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		49			
Reverse Recovery Rise Time	t _b			14		ns	

Notes:

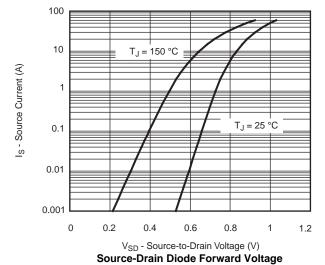
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- a. Guaranteed by design, not subject to production testing.

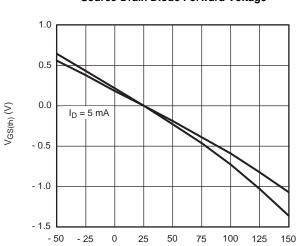
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.







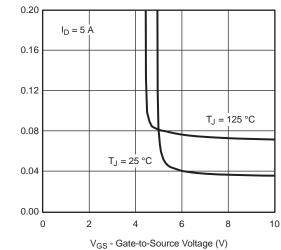




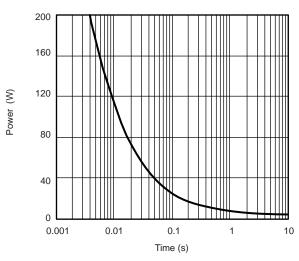
T_J - Temperature (°C)

Threshold Voltage

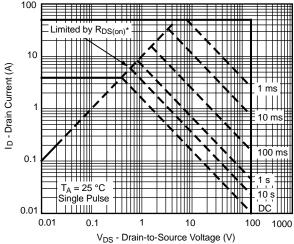
 $\mathsf{R}_{\mathsf{DS}(\mathsf{on})}$ - Drain-to-Source On-Resistance (Ω)



On-Resistance vs. Gate-to-Source Voltage



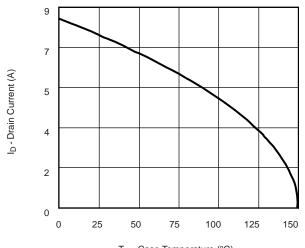
Single Pulse Power, Junction-to-Ambient



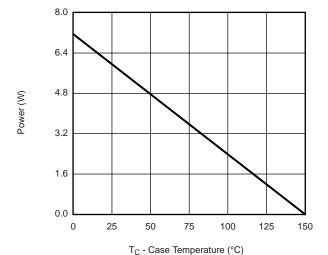
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

Safe Operating Area, Junction-to-Ambient

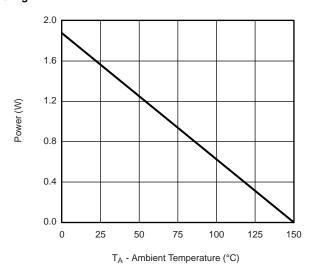




T_C - Case Temperature (°C) **Current Derating***



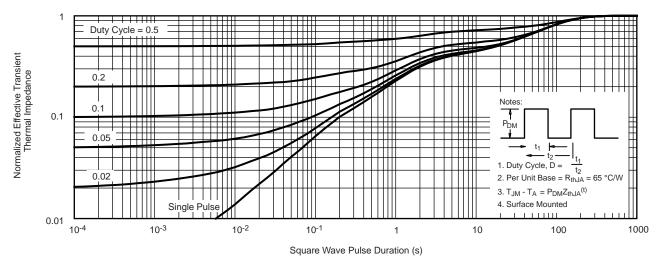
Power, Junction-to-Case



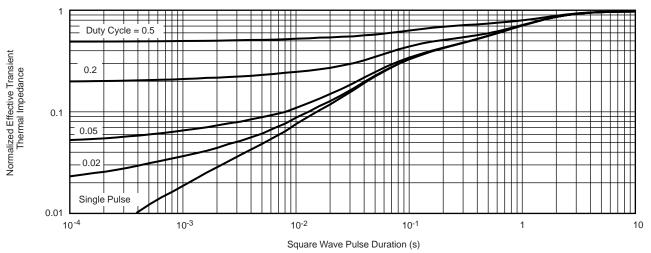
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



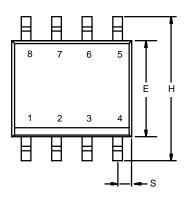
Normalized Thermal Transient Impedance, Junction-to-Foot

服务热线:400-655-8788

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SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







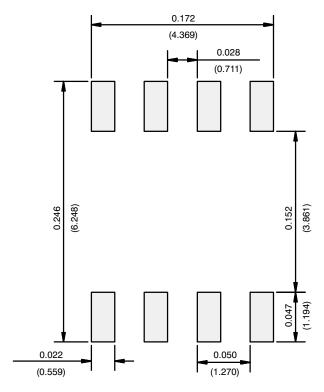
	MILLIM	IETERS	INC	HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev I 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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